

ELECTRICAL TEST PROBE FLEXIBLE SPRING TIP

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The present application is based on, and claims priority from, provisional application serial number 60/221,716, filed July 31, 2000; U.S. utility application serial number 09/895,060, filed June 29, 2001; and Patent Cooperation Treaty application serial number PCT/US01/24017, filed July 30, 2001.

BACKGROUND OF INVENTION

The present invention relates to an electrical test probe tip for use with testing instruments, and more particularly to an electrical test probe flexible coil or spring tip.

An electrical test probe generally consists of a probing head with a tip, a cable, and a connector for attaching the cable to test instruments. The probing head may have an integral or replaceable probing tip that is suitable for making an electrical contact with electrical components. The probing head is attached to a first end of the cable and the test instrument connector is attached to the opposite end of the cable. A means for connecting the probing head to ground is also generally included in the probing head. Ground provides the electrical reference point for other signal measurements, so the ground connection typically remains unchanged while the probing head is moved around to make signal measurements.

Electrical test probes are used to provide an electrical connection between electrical components and testing instruments such as oscilloscopes and other measuring, monitoring, diagnostic, and signal processing instruments. As shown in FIG. 1, a traditional test probe tip is an elongate conductive member that terminates in a conical, blunt, or rounded point.